

FCC TEST REPORT

APPLICANT Huawei Technologies Co., Ltd.

PRODUCT NAME Virtual Reality Handle

MODEL NAME **CF20**

TRADE NAME N/A

BRAND NAME HUAWEI

47 CFR Part 15 Subpart B STANDARD(S)

TEST DATE 2017-10-15 to 2017-10-20

ISSUE DATE : 2017-10-23

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

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Test Report Declaration

Applicant	Huawei Technologies Co., Ltd.
Applicant Address	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C
Manufacturer	Huawei Technologies Co., Ltd.
Manufacturer Address	Administration Building, Headquarters of Huawei Technologies Co., Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C
Product Name	Virtual Reality Handle
Model Name	CF20
Brand Name	HUAWEI
HW Version	Ver-N
SW Version	huaweivr-v1.3n
Test Standards	47 CFR Part 15 Subpart B
Test Result	PASS

Wen Zhichao Tested by

Wen Zhichao (Test Engineer)

Approved by

Andy Yeh (Technology Director)



1. Technical Information

Note: Provided by applicant

1.1. Applicant Information

Company: Huawei Technologies Co., Ltd.

Address: Administration Building, Headquarters of Huawei Technologies Co., Ltd.,

Bantian, Longgang District, Shenzhen, 518129, P.R.C

1.2. Equipment under Test (EUT) Description

EUT Type:	Virtual Reality Handle				
Serial No:	Serial No: (N/A, marked #1 by test site)				
Hardware Version:	Ver-N				
Software Version: huaweivr-v1.3n					

Power supply :	Battery				
	Brand Name:	Energizer			
	Model No.:	E92			
	Serial No.:	(N/A, marked #1 by test site)			
	Capacity:	1200mAh			
	Rated Voltage:	1.5V			

NOTE:

- The EUT is a Virtual Reality Handle which supports ISM 2.4GHz Bluetooth band.
- For a more detailed description, please refer to specification or user's manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title			
1	47 CFR Part 15	Radio Frequency Devices			

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Test Date	Result
1	15.107	Conducted Emission	N/A	N/A
2	15.109	Radiated Emission	2017.10.17	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



Test Conditions Setting

3.1. Test Mode

1	The first test mode					
The EUT configuration of the emission tests is EUT + Battery. During the measurement, the Battery was embedded into the EUT and the EUT.						
	intentional device.					

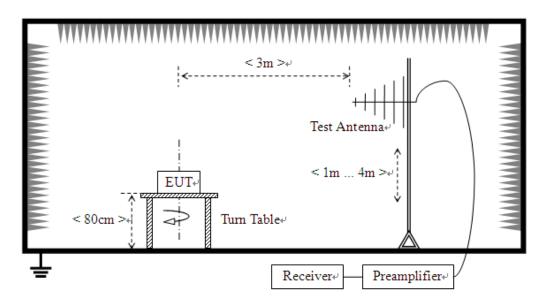


Test Setup and Equipments List

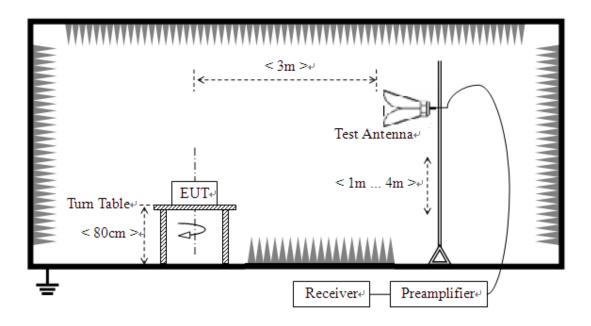
3.2.1. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz





The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on avariable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn TestAntenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

A. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date	
MXE EMI Receiver	Agilent	N9038A	MY54130016	2017.05.17	2018.05.16	
Semi-Anechoic	Changning	9m*6m*6m	N/A	2017.01.11	2018.01.10	
Chamber	Onarigining	3111 3111 3111	14/7 (2017.01.11		
Test Antenna -	Schwarzbeck	VULB 9163	9163-274	2016.12.09	2017.12.08	
Bi-Log	Scriwarzbeck	VOLD 9103	9103-274	2010.12.09	2017.12.06	
Test Antenna -	Schwarzbeck	BBHA9120C	9120C-384	2017.03.30	2018.03.29	
Horn	Scriwarzbeck	DDHA9120C	91200-304	2017.03.30	2010.03.29	

B. Test Software Utilized

Model	Version Number	Producer
MORLAB EMCR V1.2	Version 1.0	MORLAB



47 CFR Part 15B Requirements

4.1. Radiated Emission

4.1.1. Requirement

According to FCC section 15.109 (a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field Strength Limitation at 3m Measurement Dist			
range (MHz)	(μV/m)	(dBµV/m)		
30.0 - 88.0	100	20log 100		
88.0 - 216.0	150	20log 150		
216.0 - 960.0	200	20log 200		
Above 960.0	500	20log 500		

As shown in FCCsection 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level(μV/m).

4.1.2. Test Description

See section 3.2.2 of this report.

4.1.3. Frequency range of measurement

According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the



following table:

Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measure- ment range (MHz)
Below 1.705	30. 1000. 2000. 5000. 5th harmonic of the highest frequency or 40 GHz, whichever is lower.

4.1.4. Test Result

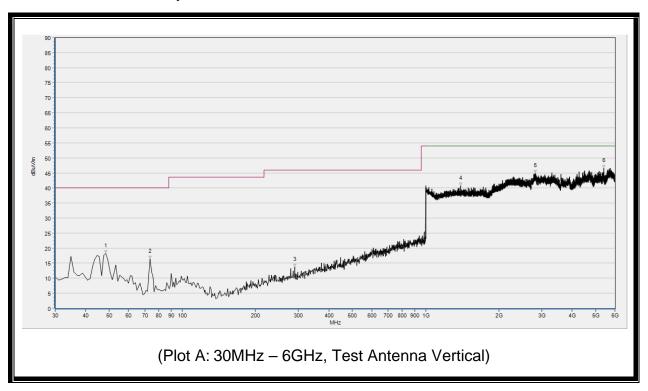
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of spurious emissions (6GHz-12.5GHz) which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

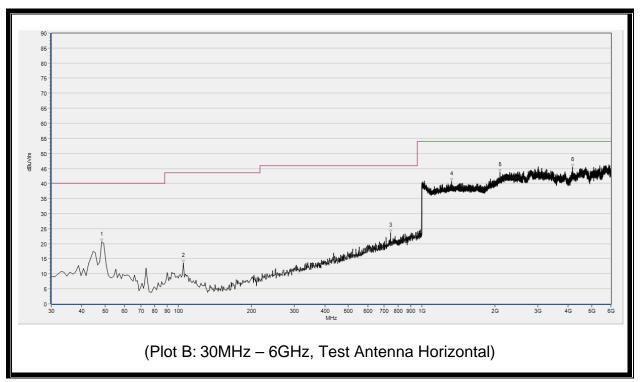


A. Test Plots and Suspicious Points:



No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m		
1	48.430	N.A.	18.22	N.A.	N.A.	40.00	N.A.	V	PASS
2	73.650	N.A.	16.50	N.A.	N.A.	40.00	N.A.	V	PASS
3	288.990	N.A.	13.69	N.A.	N.A.	46.00	N.A.	V	PASS
4	1389.867	40.65	N.A.	32.05	70.00	N.A.	54.00	V	PASS
5	2816.080	44.92	N.A.	36.74	70.00	N.A.	54.00	V	PASS
6	5395.720	46.63	N.A.	39.53	74.00	N.A.	54.00	V	PASS





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m		
1	48.430	N.A.	20.56	N.A.	N.A.	40.00	N.A.	Н	PASS
2	104.690	N.A.	13.52	N.A.	N.A.	43.50	N.A.	Н	PASS
3	744.890	N.A.	23.59	N.A.	N.A.	46.00	N.A.	Н	PASS
4	1329.067	40.71	N.A.	32.25	70.00	N.A.	54.00	Н	PASS
5	2098.667	43.79	N.A.	36.48	70.00	N.A.	54.00	Н	PASS
6	4165.840	45.48	N.A.	37.66	74.00	N.A.	54.00	Н	PASS

Result: Pass



Test Setup Photos Annex A

1. Radiated emission (30MHz-1GHz)



2. Radiated emission (above 1GHz)





Test Uncertainty Annex B

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Radiated Emission: ±3.1dB





Testing Laboratory Information

Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.		
Department:	Morlab Laboratory		
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang		
	Road, Block 67, BaoAn District, ShenZhen, GuangDong		
	Province, P. R. China		
Responsible Test Lab Manager:	Mr. Su Feng		
Telephone:	+86 755 36698555		
Facsimile:	+86 755 36698525		

Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd.			
	Morlab Laboratory			
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang			
	Road, Block 67, BaoAn District, ShenZhen, GuangDong			
	Province, P. R. China			

Accreditation Certificate

Accredited Testing Laboratory: The FCC designation number is CN1192.

(Shenzhen Morlab Communications Technology Co., Ltd.)

Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

***** END OF REPORT *****

